

Amendments to the Specification:

Please amend the first full paragraph on page 17, lines 8-13 with the following amended paragraph:

In the conventional example using the gate-level current analysis method, high-speed analyses of a current is feasible. However, only the total amount of electric current is determined. The gate-level current analysis method is sufficient in terms of power consumption but ~~is~~ insufficient in terms of EMI analysis

Please add the following new section title after the first full paragraph on page 17 (beginning on line 14):

SUMMARY OF THE INVENTION

Please amend the second full paragraph on page 17, lines 14-18 with the following amended paragraph:

~~Summary of the invention~~ The present invention has been conceived to solve the drawbacks of the conventional methods and is aimed at providing a method for enabling valuation of electromagnetic interference in LSI through simulation within a realistic period of time.

Please add the following paragraph before the first full paragraph on page 19:

Preferably, the modeling step includes a step of calculating the instantaneous electric current from information for each event, and a polygonal waveform modeling step of modeling the instantaneous current as a polygonal waveform, to thereby subject to FFT processing the information concerning a change in electric current calculated in the polygonal waveform modeling step.

Please amend the first full paragraph on page 20, lines 8-17 with the following amended paragraph:

Preferably, the modeling step includes a step of calculating the instantaneous electric current ~~for~~ from information for each event, and a ~~rectangular~~ polygonal waveform modeling step of modeling the instantaneous current as a rectangular waveform through use of a slew in an input waveform and a table representing the relationship between the width and height of a rectangular waveform, to thereby subject to FFT processing the information concerning a change in electric current calculated in the rectangular waveform modeling step.